



APPROVAL SHEET

億威電子(股)公司

Item : S3215C Crystal

Spec. no : S3215C-032768-12-20-EA

Freq : 32.768 KHz

Customer Approved	Checked By	Issued By
		

友桂電子股份有限公司

YOKETAN CORPORATION

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Fax: 86-510-88211895



RoHS Compliant



[illegible]

SPECIFICATION OF CRYSTAL UNITS

YOKETAN CORP.

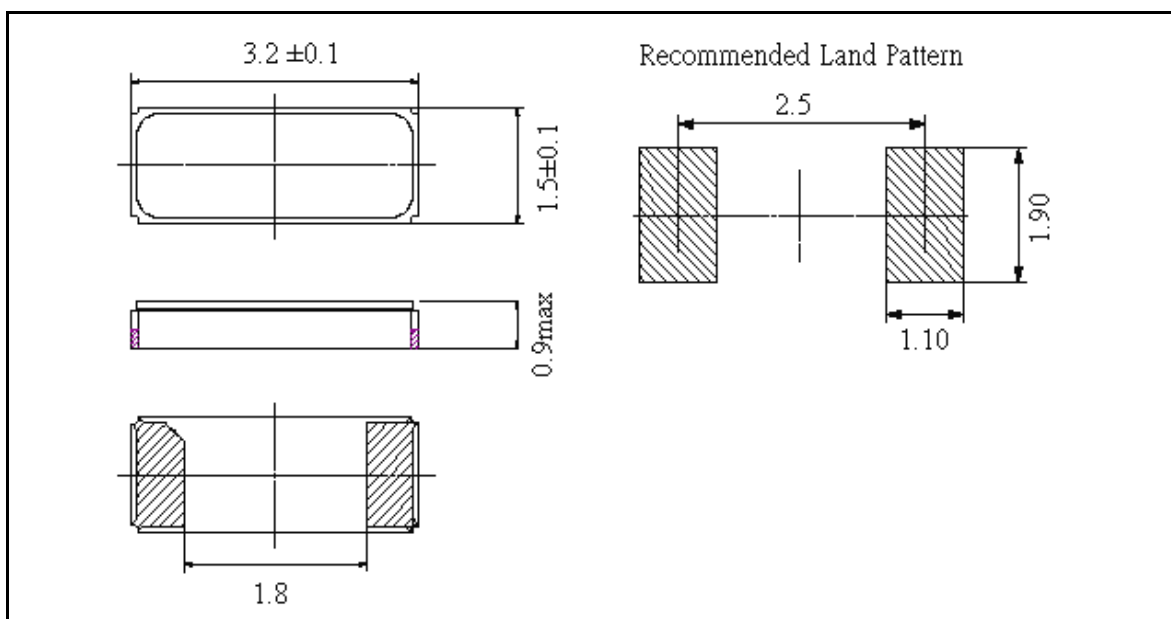
Customer : 億威

SPEC NO : S3215C-032768-12-20-EA
(Lead Free Parts)

Date : 15-Sep-11

SPECIFICATION OF CRYSTAL UNITS

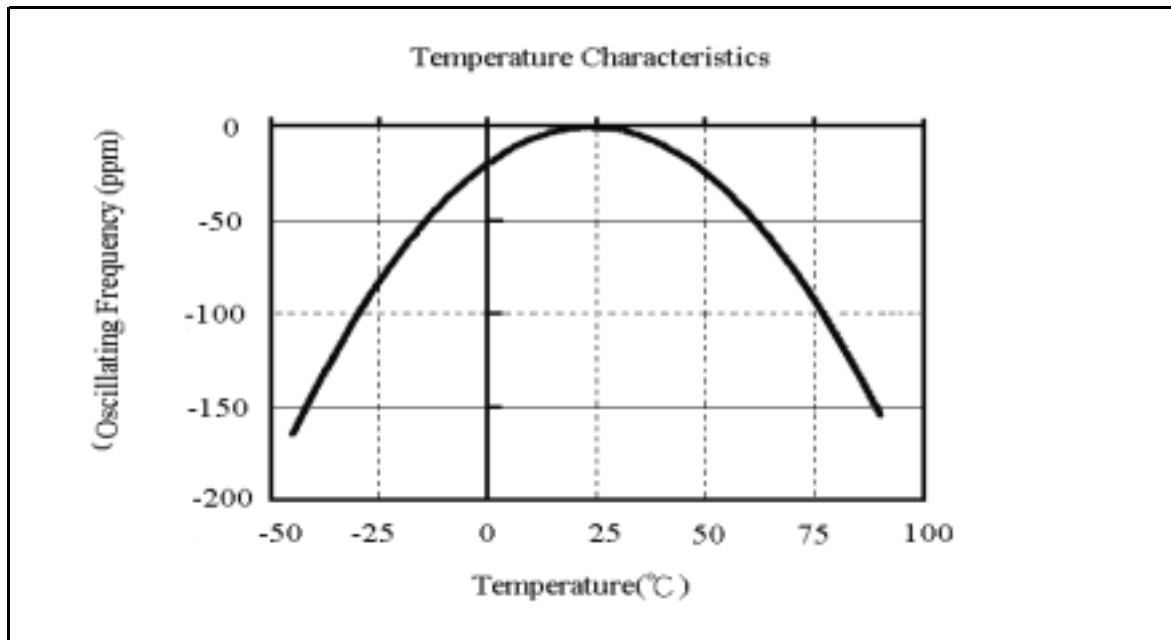
- | | |
|--------------------------------|--|
| 1 Nominal frequency | 32.768 KHz |
| 2 Frequency tolerance | $\pm 20\text{ppm}$ at $25 \pm 2^\circ\text{C}$ |
| 3 Temperature characteristics | |
| -Turnover temperature | $25 \pm 5^\circ\text{C}$ |
| -Temperature Coefficient | $-0.045 \times 10^{-6} / ^\circ\text{C}^2$ Max |
| 4 Operating temperature | -40 to 85 degrees |
| 5 Equiverent series resistance | 70k ohms Max. |
| 6 Load capacitance | 12.5pF |
| 7 Shunt capacitance | 2.0pF Max. |
| 8 Drive level | 1.0uW Max |
| 9 Storage temperature | -55 to 125 degrees |
| 10 Aging(First year) | $\pm 3\text{ppm}$ Max. |
| 11 Marking | Standard |
| 12 Unit Net of Weight: | $0.012\text{g} \pm 0.0006\text{g}$ |
| 13 Dimension (unit: mm) | |



SPECIFICATION OF CRYSTAL UNITS

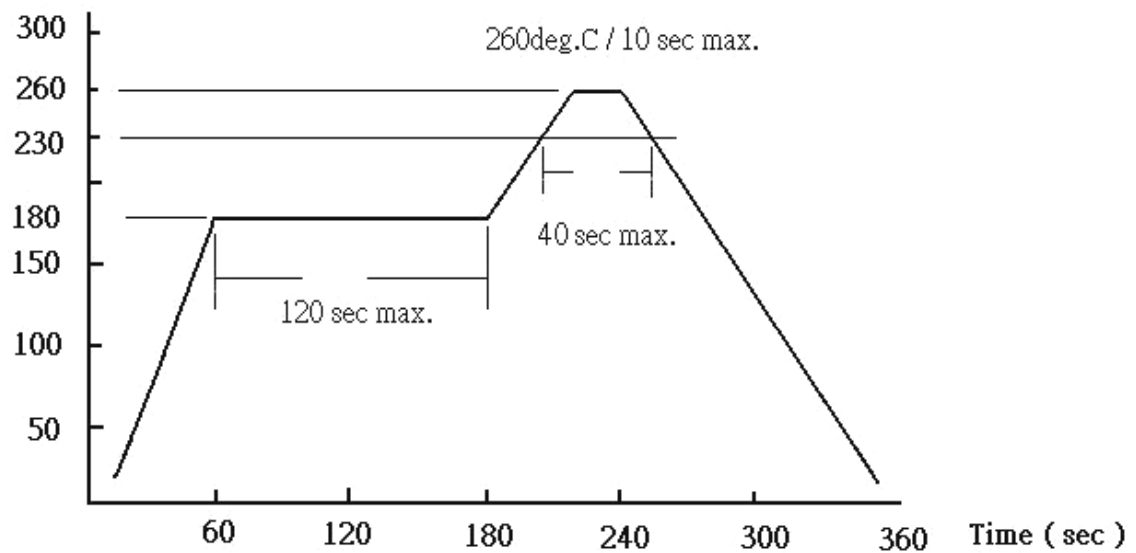
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14 Frequency VS Temperature



15 Soldering Reflow

Temp. (deg.C)



SPECIFICATION OF CRYSTAL UNITS

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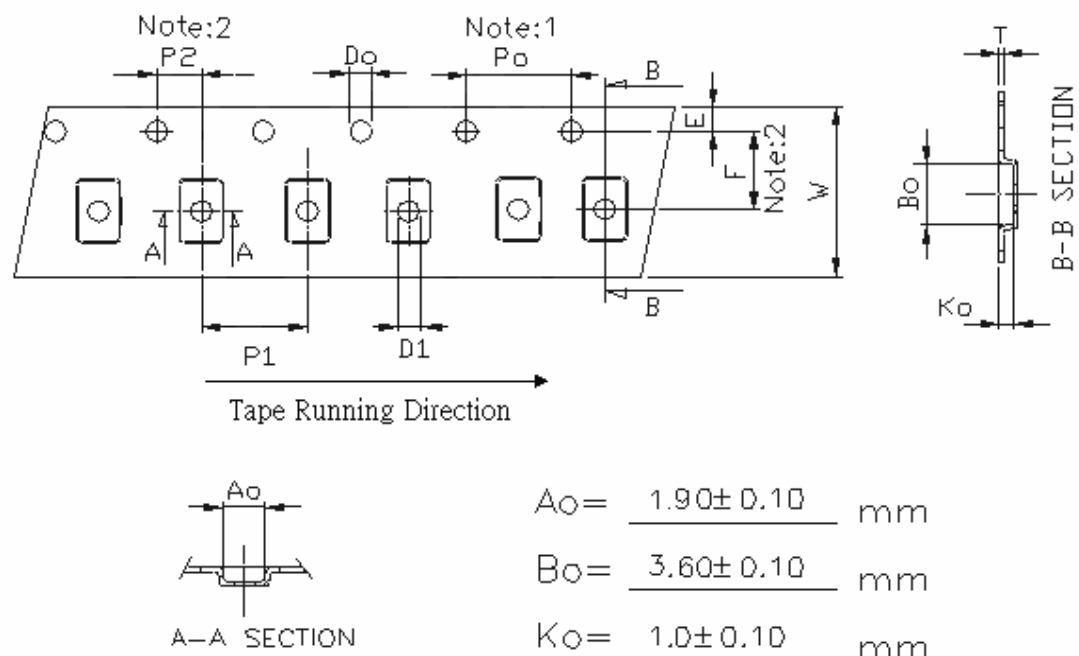
Reliability Test (applicable to 49(50) type .U type and Tuning Fork X'tal)

Test Items	Test Condition	Specification	
		Dip	SMD
1. Gross Leak Test	FC-40 125 /30sec	No continuous bubble	
2. Fine Leak Test	Bombing of He 4kg/cm ² for 2 hours	Less than 5*10 ⁻⁸ atm.c.c./sec, Helium	
3. Drop Test	a ~19.999MHz(Fund.) 100 cm height b. 20~29.999MHz(Fund.) →50 cm height c. 30~ MHz(Fund.) →20 cm height on hard wooden surface / 3 times (thickness more than 30 mm)	F ± 10PPM , C.I within spec.	F ±10PPM , C.I within spec.
4. Vibration Test	Freq. range: 10~55Hz Peak to peak amplitude:1.5mm 3 direction(X,Y,Z) , each 60min.	F ± 10PPM , C.I within spec.	F ±10PPM , C.I within spec.
5. Resistance to Soldering Test	a. IR Reflow furnace with the condition 2 times. Peak temp.260±3 , 10±1 sec.	NA	F ±10PPM , C.I within spec. For SMD type only.
	b. Dip terminals in a 245±5 solder station(pool) Dipping depth 0.5mm(Min) Dipping time 5±0.5 sec.	At least 90% by 30X magnification of each dipped area shall be covered by fresh solder. For DIP type only.	NA
6. Bending Test	Bending cycle : 1 cycle 0° - > 45° -> 0° -> 45° - > 0°	F ±5PPM , C.I within spec. For DIP type only.	NA
7. Shearing Test	Weight : 5N, Test duration : 10±1 sec	NA	F ±10PPM , C.I within spec. For SMD type only.
8. Low Temp. Exposure Test	-40±3 , 240±12 hrs	F ± 10PPM , C.I within spec.	F ±10PPM , C.I within spec.
9. Aging Test	85±3 , 240±12hrs	F ± 10PPM , C.I within spec.	F ±10PPM , C.I within spec.
10. High Temp. & Humidity Test	+85 ±5 & 85%±5% R.H. , 240±12 hrs	F ± 10PPM , C.I within spec.	F ±10PPM , C.I within spec.
11. Temperature Cycling Test	-25±3 /15±3min ~ +85±3 /15±3min 15cycles	F ± 10PPM , C.I within spec.	F ±10PPM , C.I within spec.

SPECIFICATION OF TAPE & REEL

YOKETAN CORP.

Taping



$$A_o = \frac{1.90 \pm 0.10}{\text{mm}}$$

$$B_o = \frac{3.60 \pm 0.10}{\text{mm}}$$

$$K_o = \frac{1.0 \pm 0.10}{\text{mm}}$$

Unit: mm

Symbol	Spec.
K1	-
Po	4.0 ± 0.10
P1	4.0 ± 0.10
P2	2.0 ± 0.05
Do	1.50 ± 0.10
D1	$1.0^{+0.2}_{-0}$
E	1.75 ± 0.10
F	5.50 ± 0.05
10Po	40.0 ± 0.10
W	12.0 ± 0.2
T	0.30 ± 0.05

Notice:

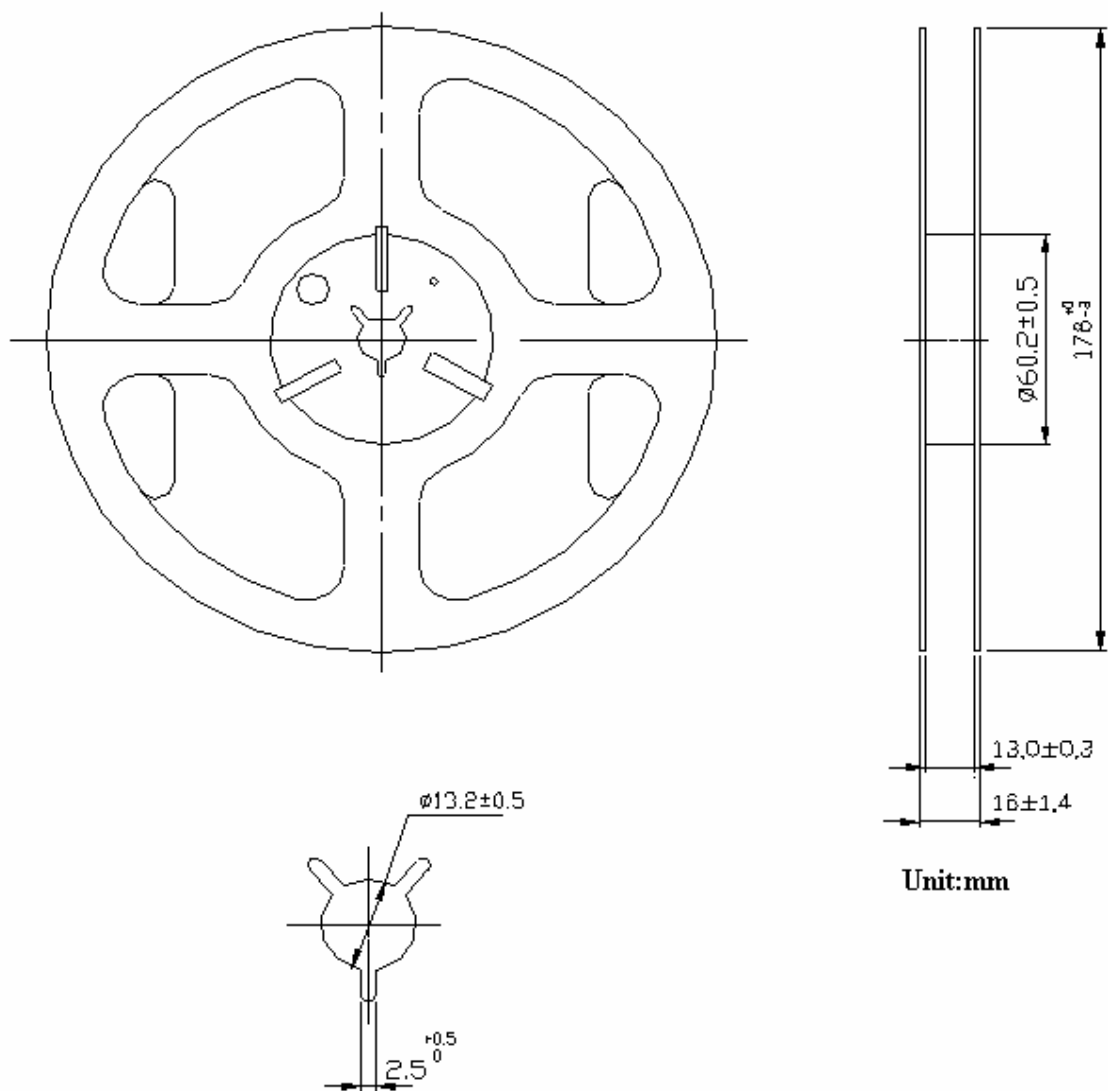
1. 10 Sprocket hole pitch cumulative tolerance is $\pm 0.1\text{mm}$
2. Pocket position relative to sprocket hole measured as true position of pocket not pocket hole.
3. Ao & Bo measured on a plane 0.3mm above the bottom of the pocket to top surface of the carrier.
4. Ko measured from a plane on the inside bottom of the pocket to the top surface of the carrier
5. Carrier camber shall be not than 1mm per 100mm through a length of 250mm.

	Date	Name	Unit : mm	
Drawn	18.Jan.2007	Leo	Title	Drawing No.
Checked	18.Jan.2007	Iris	Tape & Reel Dimension	C009-010310-X-1001
Approved	18.Jan.2007	Wan		

SPECIFICATION OF TAPE & REEL

YOKETAN CORP.

Reel



Unit:mm

Q'ty:3000pcs/reel

	Date	Name	Unit : mm	
Drawn	18.Jan.2007	Leo	Title Tape & Reel Dimension	Drawing No. C009-0713-X-1001
Checked	18.Jan.2007	Iris		
Approved	18.Jan.2007	Wan		



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測試報告/ Test Report

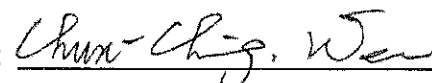
工服編號/ Application No	11-07-QAC-064
承辦日期/ Date of Receipt	2011/07/12
測試日期/ Date of Performance	2011/07/13
報告日期/ Date of Issue	2011/07/18
委託機構/ Manufacturer	友桂電子股份有限公司 YOKETAN CORPORATION
地址/ Address	台中市潭子區台中加工出口區南二路 28 號-2 28-2, Nan 2nd Road, T.E.P.Z Taichung, (42760) Taiwan, R.O.C.
樣品名稱/ Sample Description	SMD TURNING FORK
樣品型號/ Model No.	S4918. S4115. S3215. S2012
測試內容/ Report Content	A. 樣品敘述與測試結果/ Sample Information & Results B. 樣品圖片/ Sample Photo C. 流程圖/ Flow Chart

1. 送測樣品及其相關訊息均由客戶提供並已經由客戶確認無誤。/ Any sample(s) and its information listed in this document are provided and identified by clients.

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報告簽署人/ Approved by:



Laboratory Representative

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A 樣品敘述/ Sample Information

NO.1

樣品編號/ Sample No. 11-07-QAC-064

樣品名稱/ Sample Description SMD TURNING FORK

樣品型號/ Model No. S4918. S4115. S3215. S2012

測試結果/ Test Results

測試項目 Test Item(s)	儀器設備 Instruments	參考測試方法 Reference Method	測試結果/ Test Results (單位/ Unit : ppm)	
			NO.1	方法偵測極限 MDL
鉛/ Pb (CAS NO.7439-92-1)	ICP-OES	IEC 62321 Ed1: 2008 Totally Dissolved	N.D.	2.0
鎘/ Cd (CAS NO.7440-43-9)	ICP-OES	IEC 62321 Ed1: 2008 Totally Dissolved	N.D.	2.0
汞/ Hg (CAS NO.7439-97-6)	ICP-OES	IEC 62321 Ed1: 2008 Totally Dissolved	N.D.	2.0
六價鉻/ Cr ⁶⁺ (CAS NO.1333-82-0)	UV-VIS	IEC 62321 Ed1: 2008 Annex C	N.D.	2.0
多溴聯苯/ PBBs (CAS NO.059536-65-1)				
Monobromobiphenyl	GC-MS	IEC 62321 Ed1: 2008	N.D.	5.0
Dibromobiphenyl	GC-MS	IEC 62321 Ed1: 2008	N.D.	5.0
Tribromobiphenyl	GC-MS	IEC 62321 Ed1: 2008	N.D.	5.0
Tetrabromobiphenyl	GC-MS	IEC 62321 Ed1: 2008	N.D.	5.0
Pentabromobiphenyl	GC-MS	IEC 62321 Ed1: 2008	N.D.	5.0

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測試項目 Test Item(s)	儀器設備 Instruments	參考測試方法 Reference Method	測試結果/ Test Results (單位/ Unit : ppm)	
			NO.1	方法偵測極限 MDL
Hexabromobiphenyl	GC-MS	IEC 62321 Ed1: 2008	N.D.	5.0
Heptabromobiphenyl	GC-MS	IEC 62321 Ed1: 2008	N.D.	5.0
Octabromobiphenyl	GC-MS	IEC 62321 Ed1: 2008	N.D.	5.0
Nonabromobiphenyl	GC-MS	IEC 62321 Ed1: 2008	N.D.	5.0
Decabromobiphenyl	GC-MS	IEC 62321 Ed1: 2008	N.D.	5.0
多溴聯苯醚/ PBDEs (CAS NO.1163-19-5)				
Monobromodiphenyl ether	GC-MS	IEC 62321 Ed1: 2008	N.D.	5.0
Dibromodiphenyl ether	GC-MS	IEC 62321 Ed1: 2008	N.D.	5.0
Tribromodiphenyl ether	GC-MS	IEC 62321 Ed1: 2008	N.D.	5.0
Tetrabromodiphenyl ether	GC-MS	IEC 62321 Ed1: 2008	N.D.	5.0
Pentabromodiphenyl ether	GC-MS	IEC 62321 Ed1: 2008	N.D.	5.0
Hexabromodiphenyl ether	GC-MS	IEC 62321 Ed1: 2008	N.D.	5.0
Heptabromodiphenyl ether	GC-MS	IEC 62321 Ed1: 2008	N.D.	5.0
Octabromodiphenyl ether	GC-MS	IEC 62321 Ed1: 2008	N.D.	5.0
Nonabromodiphenyl ether	GC-MS	IEC 62321 Ed1: 2008	N.D.	5.0
Decabromodiphenyl ether	GC-MS	IEC 62321 Ed1: 2008	N.D.	5.0

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測試項目 Test Item(s)	儀器設備 Instruments	參考測試方法 Reference Method	測試結果/ Test Results (單位/ Unit : ppm)	
			NO.1	方法偵測極限 MDL
全氟辛酸/ PFOS				
$C_8F_{17}KO_3S$ (CAS NO. 2795-39-3)	LC-MS/MS	US EPA 3550C & US EPA 8321B	N.D.	1.0
全氟辛酸磺酸鹽/ PFOA				
$C_4HF_7O_2$ (CAS NO. 375-22-4)	LC-MS/MS	US EPA 3550C & US EPA 8321B	N.D.	1.0
$C_5HF_9O_2$ (CAS NO. 2706-90-3)	LC-MS/MS	US EPA 3550C & US EPA 8321B	N.D.	1.0
$C_6HF_{11}O_2$ (CAS NO. 307-24-4)	LC-MS/MS	US EPA 3550C & US EPA 8321B	N.D.	1.0
$C_7HF_{13}O_2$ (CAS NO. 375-85-9)	LC-MS/MS	US EPA 3550C & US EPA 8321B	N.D.	1.0
$C_8HF_{15}O_2$ (CAS NO. 335-67-1)	LC-MS/MS	US EPA 3550C & US EPA 8321B	N.D.	1.0
$C_9HF_{17}O_2$ (CAS NO. 375-95-1)	LC-MS/MS	US EPA 3550C & US EPA 8321B	N.D.	1.0
鹵素/ Halogen				
F (CAS NO. 7782-41-4)	I.C.	EN 14582	N.D.	50.0
Cl (CAS NO. 7782-50-5)	I.C.	EN 14582	N.D.	50.0
Br (CAS NO. 7726-95-6)	I.C.	EN 14582	N.D.	50.0
I (CAS NO. 7553-56-2)	I.C.	EN 14582	N.D.	50.0

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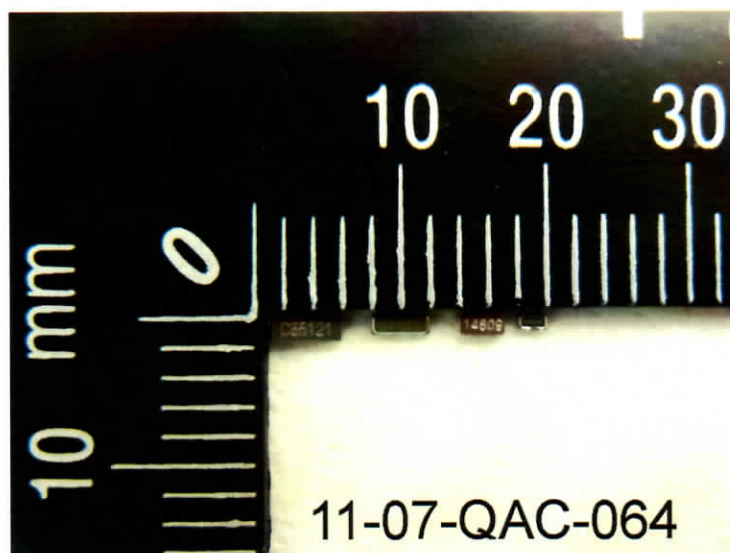
備註/ Note :

1. N.D. : 即為偵測不到/ Not Detected.
2. MDL : 方法偵測極限/ Method Detection Limitation.
3. ppm : = mg/kg (0.1% = 1000 ppm)
4. 測試儀器中英文對照/ Sino-British Contrast of the instrument
 - a. ICP-OES 感應耦合電漿原子發射光譜儀
 - b. UV-VIS 分光光度計
 - c. GC-MS 氣相層析質譜儀
 - d. IC 離子層析儀
 - e. LC-MS/MS 液相層析串聯式質譜儀
5. 測試人員/ Tested by : Ellen、ZIV
6. 檢閱人員/ Reviewed by : sujane

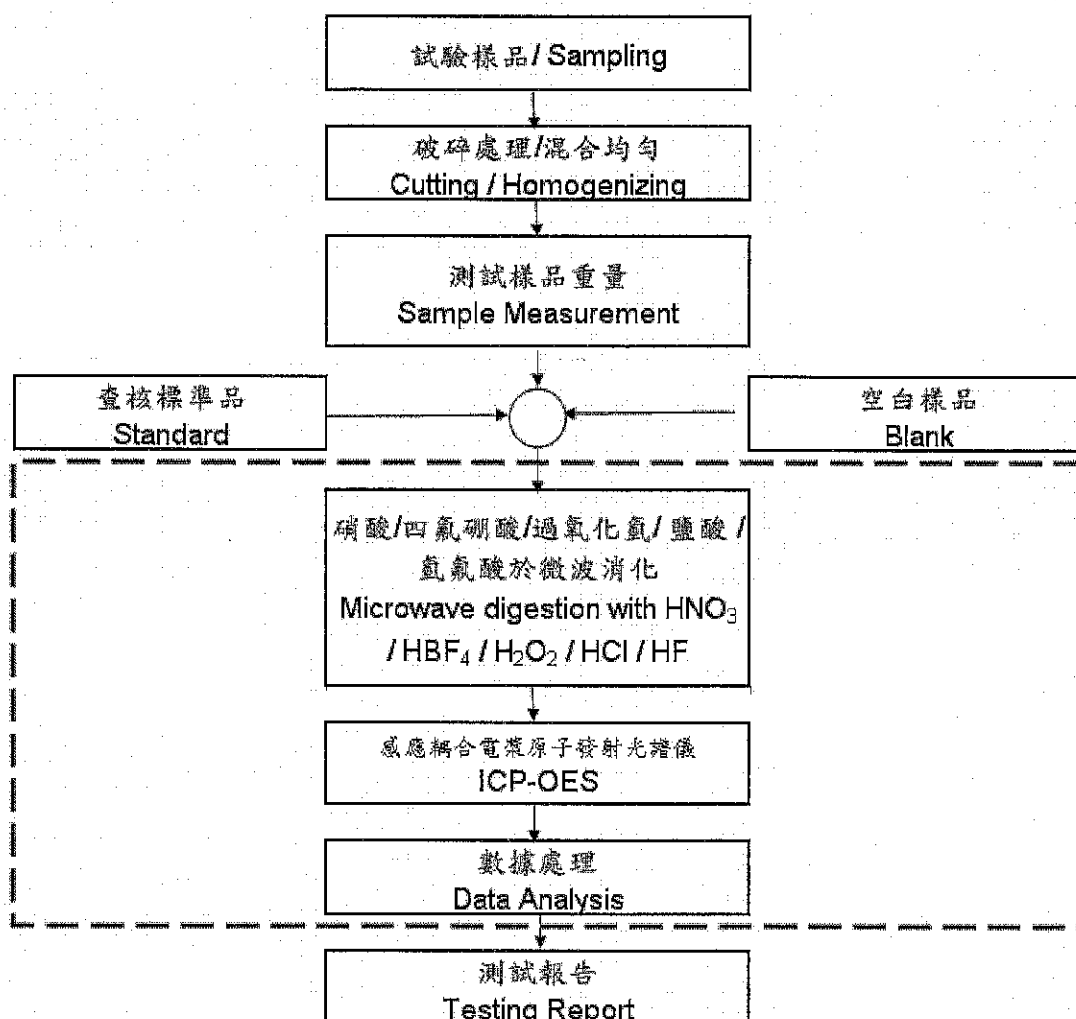
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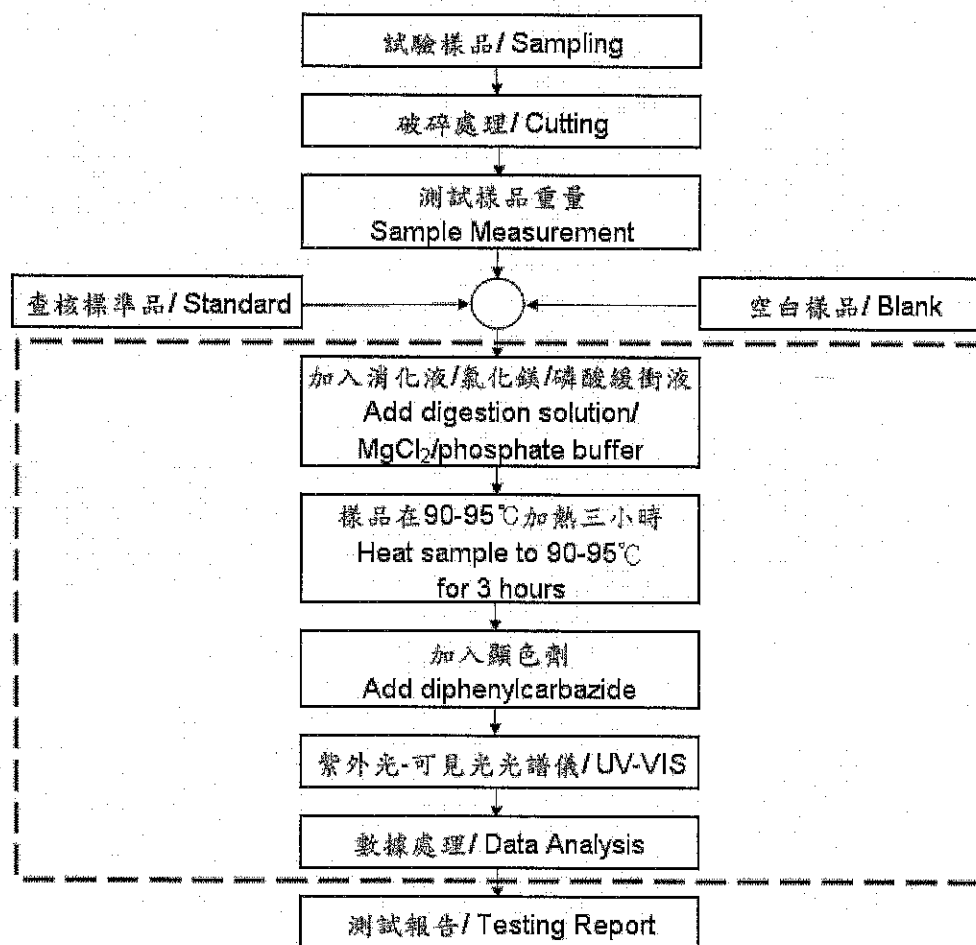
B. 樣品照片 / Sample Photo



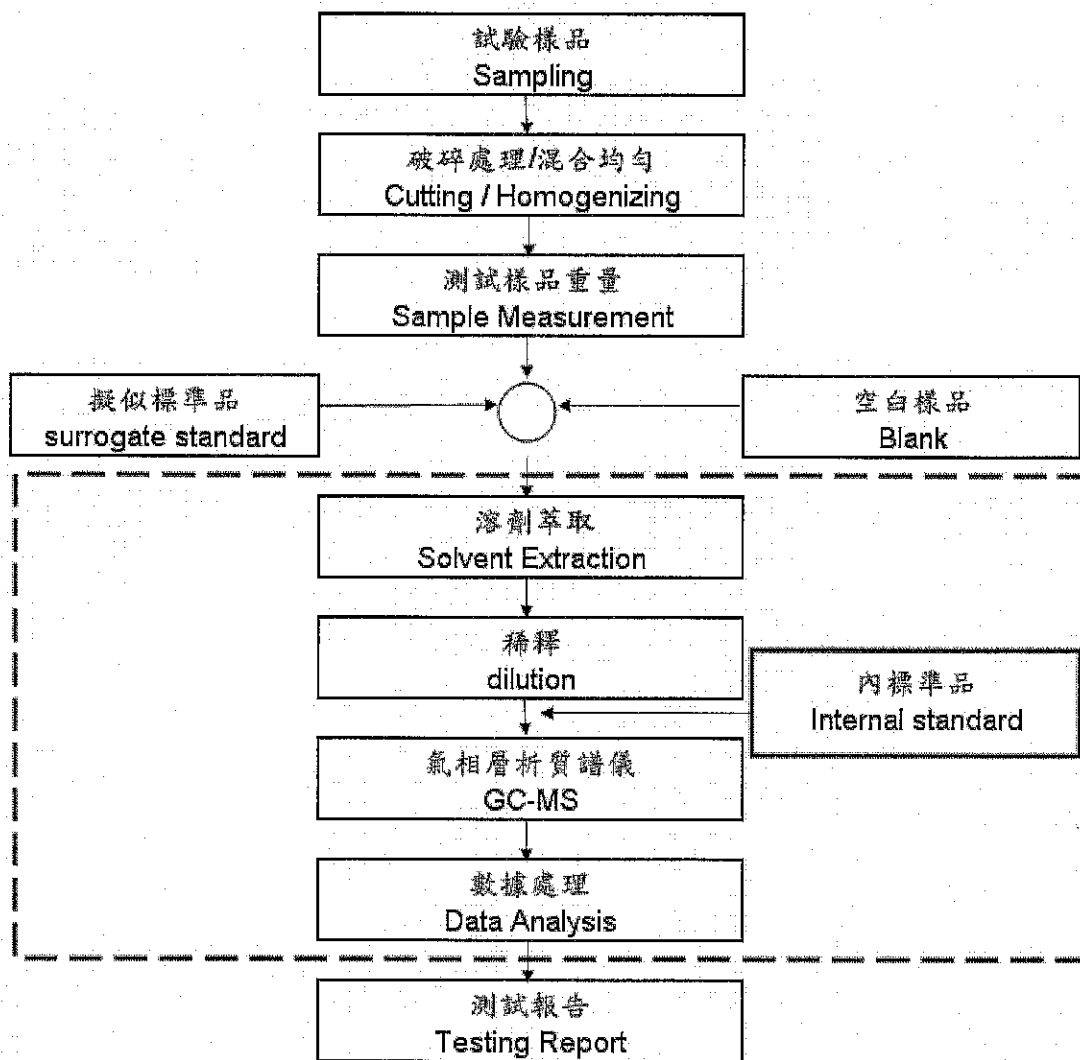
C. 流程圖/ Flow Chart



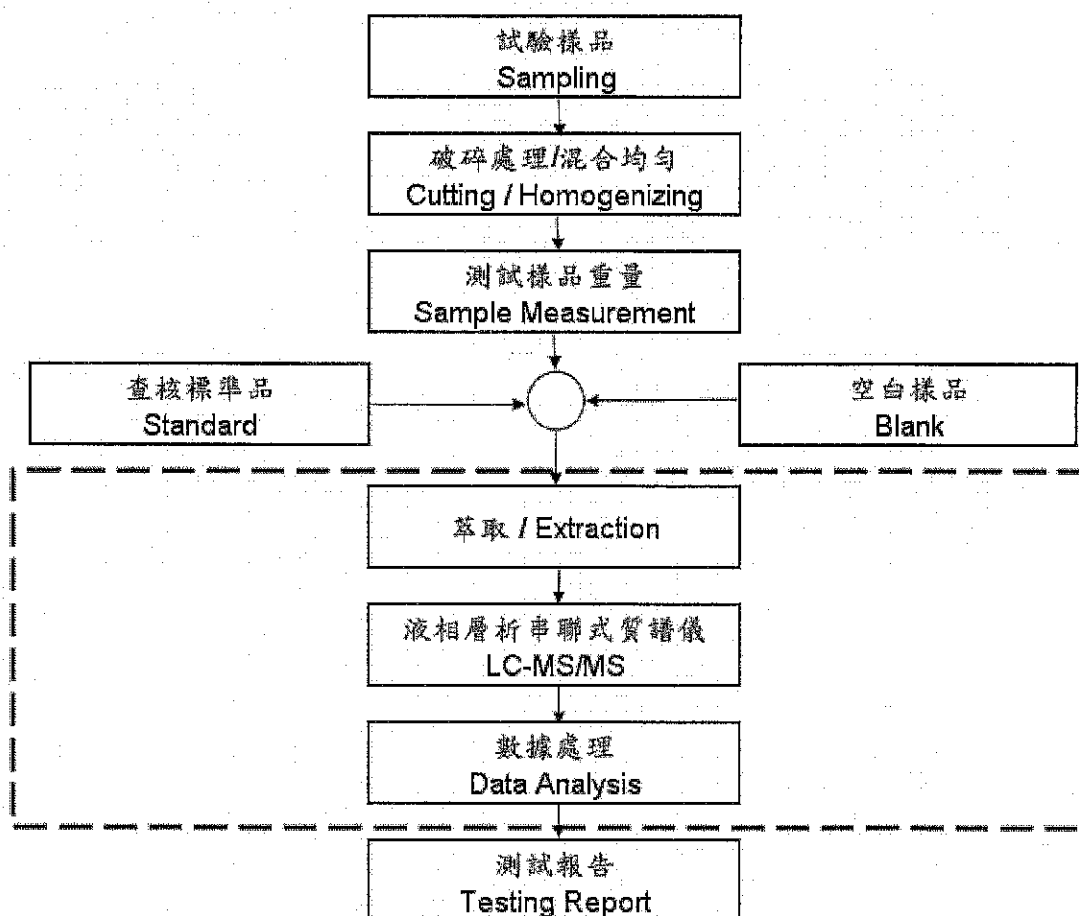
Flow Chart of Digestion-IEC 62321 for Pb、Cd、Hg (完全溶解/ Totally Dissolved)



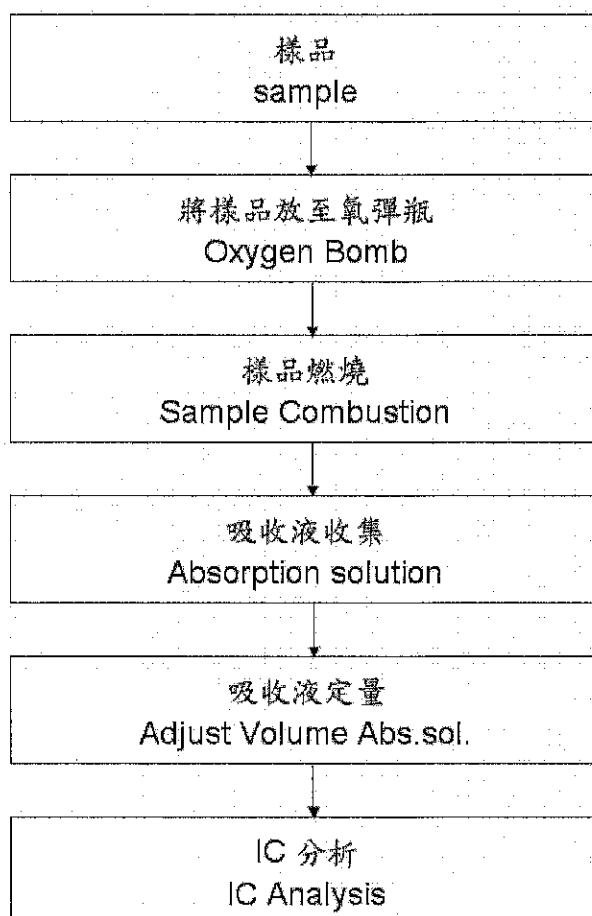
Flow Chart of Extraction-IEC 62321 for Cr⁶⁺



Flow Chart of Extraction-IEC 62321 for PBB、PBDE



Flow Chart of Extraction for PFOS/PFOA



Flow Chart of Extraction for Halogen

---報告結尾/ End of Report ---